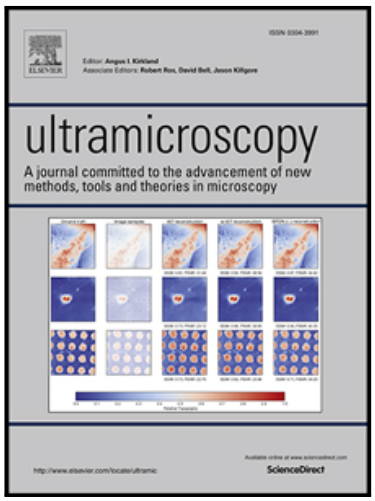

Determining oxygen relaxations at an interface: A comparative study between transmission electron microscopy techniques

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Highlights

- We report a quantitative comparison between TEM techniques
- Statistical parameter estimation theory is used to measure column positions
- Light and heavy columns are located with picometer precision for all techniques
- Precision improves by post-processing techniques (scan distortion and sample drift)
- Ultimate precision determined in counting noise limited scenario